

PA-10

Application No. 091777, 516
Examiner-GAU Fourson-2823

Prepared by JS
Date 7/12/04
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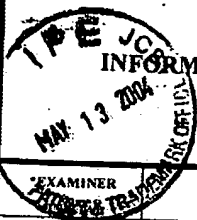
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RESPONSE

Thank you
initials (JS)

initials



INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

BREV 12370 CON3

Application Number

09/777,516

Applicant(s)

ASPAR et al.

Filing Date

February 6, 2001

Group Art Unit

2823

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

"Hydrogen-Related Complexes as the Stressing Species in High-Fluence, Hydrogen-Implanted, Single-Crystal Silicon" Cerofolini et al., *Physical Review B*, Volume 46, Number 4, 1992, pgs. 2061-2070

"Crystallographic Nature and Formation Mechanisms of Highly Irregular Structure in Implanted and Annealed Si Layers" Komarov et al., *Radiation Effects*, Volume 42, 1979, pgs. 169-178

"Observation of Blistering and Amorphization on Germanium Surface After 450 keV Ar+ION Bombardment" Kamada et al., *Radiation Effects*, Volume 28, 1976, pgs. 43-48

"Orientation Dependence of Flaking of Ion Irradiated Aluminum Single Crystals" Ono et al., *Japanese Journal of Applied Physics*, Volume 25, No. 10, 1986, pgs. 1475-1480

"High Fluence Retention of Noble Gases Implanted in Silicon" Wittmaack et al., *Radiation Effects*, Volume 39, 1978, pgs. 81-95

EXAMINER

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"Applications of Ion Beams to Materials, 1975" Carter et al., Inst. Phys. Conf. Ser. No. 28, Capter 1, 1976, pgs. 30-36

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